

# N4375E 26.5 GHz Single-Mode Fiber Lightwave Component Analyzer for 10G/40G/100G Electro-Optical Test

## General Information

The performance of digital, photonic transmission is ultimately described by the Bit Error Ratio (BER), but it is the analog nature of electro-optical subcomponents like modulators, PIN-TIA receivers and detectors that determines the performance of the entire transmission system. Only a careful design of these electro-optical components over a wide modulation signal bandwidth guarantees successful operation in the transmission system.

Keysight's N4375E Lightwave Component Analyzer (LCA) is the ideal choice to characterize such electro-optical components for 10 Gbit/s, 40 Gbit/s and 100 Gbit/s transmission systems. Using the advanced measurement capabilities of the new N52xxB series PNA Microwave Network Analyzers, all relevant S-parameter related characteristics of the device under test can be qualified from 10 MHz to 26.5 GHz.



## Productivity and Operator Guidance

The N4375E LCA has been designed with high productivity in mind: As an integrated, turn-key solution, it speeds up time-to-market when implementing the testing strategy for a new device. Compared to home-grown measurement solutions that leave the responsibility for accuracy and traceability to the user, high confidence in measurement results is maintained through self-test routines, which take uncertainty out of the calibration and measurement procedures.

An easy-to-perform, highly automated user calibration routine based on the e-Cal module, reduces the number of manual operator tasks, therefore shortening the measurement preparation time. Built-in RF switches, and the guidance provided by the instrument during user calibration and measurement setup minimize the number of re-connections and reduce operator-induced uncertainties.

## Accuracy and Traceability

The N4375E LCA is built from carefully selected opto-electronic and electronic components. Temperature-stabilized transmitter and receiver components ensure measurements are reproducible over days without user re-calibration.

Because measurements at high absolute and relative accuracy improve both, development results, and production yield, every LCA undergoes an extended factory calibration across multiple optical power levels to minimize noise and ripple in the measurement traces.

Factory calibration against reference standards traceable to national standards ensures that test results can be compared among test locations worldwide. For balanced measurements, traceability is ensured up to frequencies as high as 26.5 GHz.

## Software and Remote Control

Software and remote control are identical across the N437xB/C/D and N437xE generations of LCAs. They also share a common user interface, just like the recent PNA generations, to reduce operator training needs.

Remote control via LAN using .NET or COM interfaces, or through the industry-standard, easy-to-use SCPI interface simplifies the LCA's integration into an automated test environment. This is particularly helpful when an opto-electronic component's frequency response needs to be qualified over a wide range of parameters – a cumbersome and error-prone process if done manually.

## The Network Analyzer

The N4375E is based on the new 2- and 4-port N5222B PNA microwave network analyzer with an identical and well-known user interface across all Keysight performance network analyzers. Versions with configurable test set and bias-T integrated in the network analyzer are available. The High RF output power ensures an optical modulation index (OMI) above 50%. This offers the freedom to change between small signal analysis and large signal analysis of a device under test. True mode balanced measurements are possible with 4-port, dual source network analyzers.

## Target Test Devices

Transmitters and receivers are typically tested for their frequency response over a range of bias voltages, optical input power levels, operating currents and ambient temperatures. The LCA's built-in optical power meter allows checking and controlling the user-selectable operating power, but also gives an indication of a bent fiber or a bad connection. The optional, auxiliary PMF input (option 050) enables the measurement of optically filtered/ demultiplexed O/E devices at specific wavelengths as proposed by the IEEE 802.3 standards and MSAs, or the verification of S-parameters over wavelength using an external tunable laser. With the LCA's high update rate, parameters can be adjusted to determine the optimum operating point of such devices.

### Transmitters (E/O)

Mach-Zehnder modulators (MZM), electro-absorption modulators (EAM), directly modulated lasers, driver amplifier – modulator hybrids and transmitter optical subassemblies (TOSA) are among the most common optical transmitter components that can be characterized using the LCA. Dual-drive optical modulators and transmitters with differential electrical inputs can also be characterized using 4-port PNA versions of the LCA.

### Receivers (O/E)

PIN photodiodes, avalanche photodiodes (APD), receiver optical subassemblies (ROSA) and integrated PIN-TIA receivers are examples of optical receiver components typically tested with an LCA. Moreover, 4-port PNA versions of the LCA can characterize PIN-TIA combinations with differential output for common-mode rejection and gain imbalance.

### Optical Devices (O/O)

Transmission systems are typically tested for bandwidth and group delay using an LCA. Passive optical components can be tested for insertion loss, bandwidth limitations, and optical group delay.

### Electronic Devices (E/E)

Measurements of amplifiers, filters and transmission lines focus on transmission bandwidth, insertion loss or gain, impedance match and group delay. Such purely electronic measurements are possible with the network analyzer that is part of the LCA.

## Measurement Capabilities

Responsivity (S21, amplitude and phase)	Absolute frequency response, such as the conversion efficiency of a transmitter, or the responsivity and gain of a receiver
	Relative frequency response, such as filter shapes or amplifier gain
	3-dB bandwidth of the electro-optical or electrical transfer function
	Group Delay vs. frequency of the transfer function
Reflectivity (S11 or S22, amplitude and phase)	Optical Insertion Loss (IL)
	Electrical reflectivity at the RF port
Balanced measurements (requires 4-port PNA)	Impedance match
	Differential gain, gain imbalance
	Common-mode rejection, common-mode transfer function

## Key Specifications

### Operating frequency range

10 MHz to 26.5 GHz

### Relative frequency response uncertainty

± 0.5 dB @ 20 GHz (typical)

### Absolute frequency response uncertainty

± 1.5 dB @ 20 GHz (typical)

### Noise floor

–76 dB(A/W) for O/E measurements @ 20 GHz

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–86 dB(W/A) for E/O measurements @ 20 GHz

### Typical phase uncertainty

± 2.0°

### Transmitter wavelength

1550 nm ± 20 nm

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1310 nm ± 20 nm

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1290 to 1610 nm with external source input

### Built-in optical power meter

For fast transmitter power verification and indication of breaks, bends and bad connections

### Powerful remote control

Programming interface based on Microsoft .NET or COM and SCPI

### Auxiliary optical input (option 050)

PMF input, connects an external laser source through a PMF optical switch to the internal modulator

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## Definitions

Generally, all specifications are valid at the stated operating and measurement conditions and settings, with uninterrupted line voltage.

## Specifications (guaranteed)

Describes warranted product performance that is valid under the specified conditions. Specifications include guard bands to account for the expected statistical performance distribution, measurement uncertainties, changes in performance due to environmental changes and aging of components.

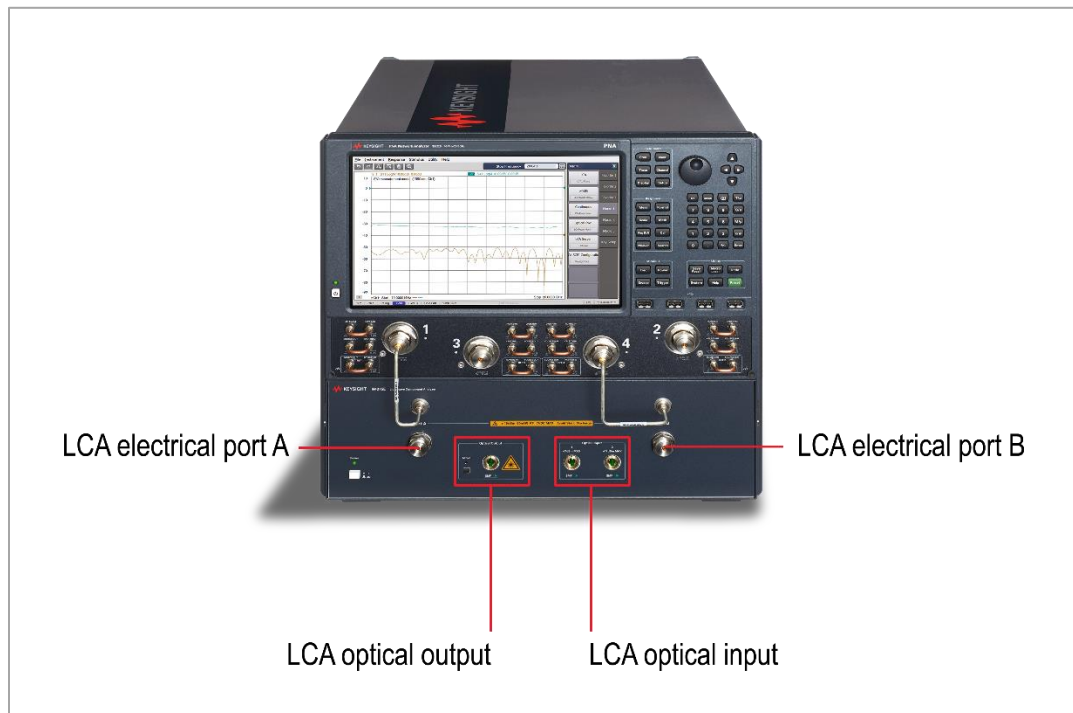
## Typical values (characteristics)

Describe the product performance that is usually met but not guaranteed. Typical values are based on data from a representative set of instruments.

## General characteristics

Give additional information for using the instrument. These are general descriptive terms that do not imply a level of performance.

## LCA Inputs and Outputs



## Explanation of Terms

### Responsivity

For electro-optical devices (e.g. modulators) this describes the ratio of the optical modulated output signal power to the RF amplitude at the device input.

For opto-electrical devices (e.g. photodiodes) this describes the ratio of the RF amplitude at the device output to the modulated optical signal input power.

### Relative frequency response uncertainty

Describes the maximum deviation of the shape of a measured trace from the (unknown) real trace. This specification has strong influence on the accuracy of the 3-dB cut-off frequency determined for the device under test.

### Absolute frequency response uncertainty

Describes the maximum difference between any amplitude point of the measured trace and the (unknown) real value. This specification is useful to determine the absolute responsivity of the device versus modulation frequency.

### Frequency response repeatability

Describes the deviation of repeated measurement without changing any parameter or connection relative to the average of this measurements.

### Minimum measurable frequency response

Describes the average measured responsivity when no modulation signal is present at the device under test. This represents the noise floor of the measurement system.

## Keysight N4375E Specifications

### Measurement conditions

- Modulation frequency range from 10 MHz to 26.5 GHz
- Forward RF power: +5 dBm
- Reverse RF power: -5 dBm
- Number of averages: 1
- 100 Hz IFBW (“Reduce IF bandwidth at low frequency” enabled) with modulation frequency step size 10 MHz and measurement points on a 10 MHz raster (if not stated otherwise)
- Network analyzer set to “stepped sweep – sweep moves in discrete steps”
- Network analyzer configured in normal coupler configuration (“CPLR ARM” to “RCVB B in”, “SOURCE OUT” to “CPLR THRU”) on network analyzer port connected to LCA receiver
- After full two-port electrical calibration using an Electronic Calibration Module, Keysight N4691D, at constant temperature ( $\pm 1$  °C) with network analyzer set to -10 dBm electrical output power
- Modulation-bias optimization set to “every sweep”
- Measurement frequency grid equals electrical calibration grid
- Tested from PNA Port 1 to Port 2, respectively from PNA Port 1 to Port 4 for 4-port PNA
- DUT signal delay  $\leq 0.1/IF-BW$
- Specified temperature range: +20 °C to +26 °C
- After warm-up time of 90 minutes
- Using high quality electrical and optical connectors in perfect condition
- Using internal laser source

The optical test set always has angled connectors. Depending on the selected option (021 straight, 022 angled) the appropriate jumper cable will be delivered. This jumper cable must always be used to connect the device under test to the optical test set to protect the test set’s connectors and is required for performance tests.

## Transmitter and Receiver Specifications

Optical Test Set		
Operation frequency range		10 MHz to 26.5 GHz
Connector type	Optical input	SMF angled with Keysight universal connector interface
	Optical output	
	Optical source input (rear, option 050)	9/125 $\mu\text{m}$ Panda PMF angled, with Keysight universal connector interface, TE mode in slow axis, in line with connector key
	RF	3.5 mm male
LCA optical input		
Operating input wavelength range		1250 nm to 1640 nm <sup>3</sup>
Maximum linear average input power <sup>1</sup>	Optical input 1	+4 dBm
	Optical input 2	+14 dBm
Maximum safe average input power	Optical input 1	+7 dBm
	Optical input 2	+17 dBm
Optical return loss (typical) <sup>1</sup>		> 27 dBo
Average power measurement range <sup>1</sup>	Optical input 1	-25 dBm to +4 dBm
	Optical input 2	-15 dBm to +14 dBm
Average power measurement uncertainty (typical) <sup>1</sup>		$\pm 0.5$ dBo
LCA optical output (Internal source)		
Optical modulation index (OMI) at 10 GHz (typical)		> 27% @ +5 dBm RF power
		> 47% @ +10 dBm RF power
Output wavelength	Option 100, 102	(1310 $\pm$ 20) nm
	Option 101, 102	(1550 $\pm$ 20) nm
Average output power range		-2 dBm to +4 dBm
Average output power uncertainty (typical) <sup>2</sup>		$\pm 0.5$ dBo
Average output power stability, 15 minutes (typical)		$\pm 0.5$ dBo

<sup>1</sup> Wavelength within range as specified for LCA optical output.

<sup>2</sup> After modulator optimization.

<sup>3</sup> Excluding water absorption wavelengths.



## Optical Test Set

### External optical source input (-050)

Recommended optical input power <sup>4</sup>	+8 to +15 dBm
Optical input power damage level	+20 dBm
Typical loss at quadrature bias point	9 dB
Operating input wavelength range	1290 nm to 1610 nm <sup>3</sup>

### LCA RF test port input

Maximum safe input level at port A or B	+15 dBm RF, 7V DC
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<sup>3</sup> Excluding water absorption wavelengths.

<sup>4</sup> Required source characteristics: SMSR > 15 dB, line width < 10 MHz, power stability < 0.1 dB pp, PER > 20 dB, unmodulated, single mode fiber.

## Specifications for Electrical to Optical Measurements at 1310 nm (E/O Mode)

N4375E with network analyzer: N5222B option 200, 201, 219, 400, 401, or 419.

Specifications are valid under the stated measurement conditions.

- At optical input 1 (“+ 7 dBm max”). At optical input 2 (“+ 17 dBm max”), specifications are typically the same for 10 dB higher incident average and modulated optical power.
- For wavelength: (1310 ± 20) nm (option 100, 102).

System performance	DUT response	0.05 GHz to 0.2 GHz	0.2 GHz to 0.7 GHz	0.7 GHz to 20 GHz	20 GHz to 26.5 GHz
	≥ -22 dB(W/A) <sup>1</sup>	± 0.7 dBe typical	± 0.7 dBe (± 0.5 dBe, typical)	± 0.7 dBe (± 0.5 dBe, typical)	± 0.5 dBe, typical
Relative frequency response uncertainty	≥ -32 dB(W/A) (typical)	± 0.7 dBe	± 0.5 dBe	± 0.5 dBe	± 0.5 dBe
	≥ -42 dB(W/A) (typical)	± 0.8 dBe	± 0.6 dBe	± 0.6 dBe	± 0.6 dBe
Absolute frequency response uncertainty	≥ -22 dB(W/A) <sup>1</sup>	± 1.7 dBe typical	± 2.2 dBe (± 1.5 dBe, typical)	± 2.2 dBe (± 1.5 dBe, typical)	± 1.5 dBe, typical
	≥ -22 dB(W/A) <sup>1</sup>	± 0.1 dBe	± 0.1 dBe	± 0.12 dBe	± 0.12 dBe
Frequency response repeatability (typical)	≥ -32 dB(W/A)	± 0.1 dBe	± 0.1 dBe	± 0.12 dBe	± 0.12 dBe
	≥ -42 dB(W/A)	± 0.19 dBe	± 0.15 dBe	± 0.17 dBe	± 0.17 dBe
Min. measurable freq. response (noise floor) <sup>2,3</sup>	-	-60 dB(W/A)	-86 dB(W/A)	-86 dB(W/A)	-80 dB(W/A), typical
Phase uncertainty (typical) <sup>4</sup>	≥ -42 dB(W/A) <sup>1</sup>	-	± 2.0°	± 2.0°	± 2.0°
Group delay uncertainty	-	Derived from phase uncertainty, see section “Group delay uncertainty”. Example: ± 2.0° → ± 8 ps (1 GHz aperture)			

<sup>1</sup> For DUT response max. -13 dB(W/A).

<sup>2</sup> IFBW = 10 Hz.

<sup>3</sup> Average value over frequency range.

<sup>4</sup> Except phase wrap aliasing (Example: A DUT group delay of 5 ns (1 m cable length) requires a frequency step size of ≤ 0.2 GHz to avoid phase wraps). Excluding a constant group delay offset of < ± 0.3 ns typical. (Cable length uncertainty < ± 0.06 m). A constant group delay offset leads to a phase offset  $\Delta\Phi = 360^\circ \times \Delta GD \times f_{mod}$  (in deg).

## Specifications for Electrical to Optical Measurements at 1550 nm (E/O Mode)

N4375E with network analyzer: N5222B option 200, 201, 219, 400, 401, or 419.

Specifications are valid under the stated measurement conditions.

- At optical input 1 (“+ 7 dBm max”). At optical input 2 (“+ 17 dBm max”), specifications are typically the same for 10 dB higher incident average and modulated optical power.
- For wavelength: (1550 ± 20) nm (option 101, 102).

System performance	DUT response	0.05 GHz to 0.2 GHz	0.2 GHz to 0.7 GHz	0.7 GHz to 20 GHz	20 GHz to 26.5 GHz
	≥ -22 dB(W/A) <sup>1</sup>	± 0.7 dBe, typical	± 0.7 dBe (± 0.5 dBe, typical)	± 0.7 dBe (± 0.5 dBe, typical)	± 0.5 dBe, typical
Relative frequency response uncertainty	≥ -32 dB(W/A) (typical)	± 0.7 dBe	± 0.5 dBe	± 0.5 dBe	± 0.5 dBe
	≥ -42 dB(W/A) (typical)	± 0.8 dBe	± 0.6 dBe	± 0.6 dBe	± 0.6 dBe
Absolute frequency response uncertainty	≥ -22 dB(W/A) <sup>1</sup>	± 1.7 dBe, typical	± 1.7 dBe (± 1.5 dBe, typical)	± 1.8 dBe (± 1.5 dBe, typical)	± 1.5 dBe, typical
	≥ -22 dB(W/A) <sup>1</sup>	± 0.02 dBe	± 0.02 dBe	± 0.05 dBe	± 0.05 dBe
Frequency response repeatability (typical)	≥ -32 dB(W/A)	± 0.06 dBe	± 0.02 dBe	± 0.05 dBe	± 0.05 dBe
	≥ -42 dB(W/A)	± 0.17 dBe	± 0.03 dBe	± 0.07 dBe	± 0.07 dBe
Min. measurable freq. response (noise floor) <sup>2,3</sup>	-	-60 dB(W/A)	-86 dB(W/A)	-86 dB(W/A)	-80 dB(W/A), typical
Phase uncertainty (typical) <sup>4</sup>	≥ -42 dB(W/A) <sup>1</sup>	-	± 2.0°	± 2.0°	± 2.0°
Group delay uncertainty	-	Derived from phase uncertainty, see section “Group delay uncertainty”. Example: ± 2.0° → ± 8 ps (1 GHz aperture)			

<sup>1</sup> For DUT response max. +7 dB(W/A).

<sup>2</sup> IFBW = 10 Hz.

<sup>3</sup> Average value over frequency range.

<sup>4</sup> Except phase wrap aliasing (Example: A DUT group delay of 5 ns (1 m cable length) requires a frequency step size of ≤ 0.2 GHz to avoid phase wraps). Excluding a constant group delay offset of < ± 0.3 ns typical. (Cable length uncertainty < ± 0.06 m). A constant group delay offset leads to a phase offset  $\Delta\Phi = 360^\circ \times \Delta GD \times f_{\text{mod}}$  (in deg).

## Specifications for Optical to Electrical Measurements at 1310 nm (O/E Mode)

N4375E with network analyzer: N5222B option 200, 201, 219, 400, 401, or 419.

Specifications are valid under the stated measurement conditions.

- For external source optical input (option 050), all specifications are typical.<sup>2, 5, 6</sup>
- For wavelength: (1310 ± 10) nm (option 100, 102).

System performance	DUT response	0.05 GHz to 0.2 GHz	0.2 GHz to 0.7 GHz	0.7 GHz to 20 GHz	20 GHz to 26.5 GHz
Relative frequency response uncertainty <sup>2</sup>	≥ -36 dB(A/W) <sup>1</sup>	± 0.7 dBe, typical	± 0.7 dBe (± 0.5 dBe) <sup>7</sup>	± 0.8 dBe (± 0.5 dBe) <sup>7</sup>	± 0.5 dBe, typical <sup>7</sup>
Absolute frequency response uncertainty <sup>2</sup>	≥ -46 dB(A/W) (typical)	± 0.8 dBe	± 0.7 dBe	± 0.8 dBe	± 0.8 dBe
Frequency response repeatability (typical) <sup>2</sup>	≥ -36 dB(A/W) <sup>1</sup>	± 1.7 dBe, typical <sup>7</sup>	± 2.0 dBe (± 1.6 dBe) <sup>7</sup>	± 2.1 dBe (± 1.7 dBe) <sup>7</sup>	± 1.7 dBe, typical <sup>7</sup>
Min. measurable freq. response (noise floor) <sup>2, 3, 4</sup>	-	-49 dB(A/W)	-72 dB(A/W)	-76 dB(A/W)	-76 dB(A/W), typical
Phase uncertainty (typical) <sup>2, 8</sup>	≥ -36 dB(A/W) <sup>1</sup>	-	± 2.0°	± 2.0°	± 2.0°
Group delay uncertainty	-	Derived from phase uncertainty, see section "Group delay uncertainty". Example: ± 2.0° → ± 8 ps (1 GHz aperture)			

<sup>1</sup> DUT response max. +10 dB(A/W).

<sup>2</sup> For +4 dBm average output power from LCA optical output.

<sup>3</sup> IFBW = 10 Hz.

<sup>4</sup> Average value over frequency range.

<sup>5</sup> After CW responsivity and user calibration with external source.

<sup>6</sup> Requires option 100 or 102.

<sup>7</sup> Typical, with internal source.

<sup>8</sup> Except phase wrap aliasing (Example: A DUT group delay of 5 ns (1 m cable length) requires a frequency step size of ≤ 0.2 GHz to avoid phase wraps). Excluding a constant group delay offset of < ± 0.3 ns typical. (Cable length uncertainty < ± 0.06 m). A constant group delay offset leads to a phase offset  $\Delta\Phi = 360^\circ \times \Delta\text{GD} \times \text{fmod}$  (in deg).

## Specifications for Optical to Electrical Measurements at 1550 nm (O/E Mode)

N4373E with network analyzer: N5222B option 200, 201, 219, 400, 401, or 419.

Specifications are valid under the stated measurement conditions.

- For external source optical input (option 050), all specifications are typical.<sup>2, 5, 6</sup>
- For wavelength: (1550 ± 20) nm (option 101, 102).

System performance	DUT response	0.05 GHz to 0.2 GHz	0.2 GHz to 0.7 GHz	0.7 GHz to 20 GHz	20 GHz to 26.5 GHz
Relative frequency response uncertainty <sup>2</sup>	≥ -36 dB(A/W) <sup>1</sup>	± 0.7 dBe, typical	± 0.7 dBe (± 0.5 dBe) <sup>7</sup>	± 0.8 dBe (± 0.5 dBe) <sup>7</sup>	± 0.5 dBe, typical <sup>7</sup>
Absolute frequency response uncertainty <sup>2</sup>	≥ -46 dB(A/W) (typical)	± 0.8 dBe	± 0.7 dBe	± 0.8 dBe	± 0.8 dBe
Frequency response repeatability (typical) <sup>2</sup>	≥ -36 dB(A/W) <sup>1</sup>	± 1.5 dBe <sup>7</sup>	± 1.8 dBe (± 1.5 dBe) <sup>7</sup>	± 1.8 dBe (± 1.5 dBe) <sup>7</sup>	± 1.8 dBe, typical <sup>7</sup>
Min. measurable freq. response (noise floor) <sup>2, 3, 4</sup>	≥ -36 dB(A/W) <sup>1</sup>	± 0.15 dBe	± 0.05 dBe	± 0.05 dBe	± 0.05 dBe
Phase uncertainty (typical) <sup>2, 8</sup>	≥ -46 dB(A/W)	± 0.25 dBe	± 0.1 dBe	± 0.1 dBe	± 0.1 dBe
Group delay uncertainty	-	-49 dB(A/W)	-72 dB(A/W)	-76 dB(A/W)	-76 dB(A/W), typical
Phase uncertainty (typical) <sup>2, 8</sup>	≥ -36 dB(A/W) <sup>1</sup>	-	± 2.0°	± 2.0°	± 2.0°
Group delay uncertainty	-	Derived from phase uncertainty, see section "Group delay uncertainty". Example: ± 2.0° → ± 8 ps (1 GHz aperture)			

<sup>1</sup> DUT response max. +10 dB(A/W).

<sup>2</sup> For +4 dBm average output power from LCA optical output.

<sup>3</sup> IFBW = 10 Hz.

<sup>4</sup> Average value over frequency range.

<sup>5</sup> After CW responsivity and user calibration with external source.

<sup>6</sup> Requires option 101 or 102.

<sup>7</sup> Typical, with internal source.

<sup>8</sup> Except phase wrap aliasing (Example: A DUT group delay of 5 ns (1 m cable length) requires a frequency step size of ≤ 0.2 GHz to avoid phase wraps). Excluding a constant group delay offset of < ± 0.3 ns typical. (Cable length uncertainty < ± 0.06 m). A constant group delay offset leads to a phase offset  $\Delta\Phi = 360^\circ \times \Delta\text{GD} \times \text{fmod}$  (in deg).

## Specifications for Optical to Optical Measurements at 1310 nm (O/O Mode)

N4373E with network analyzer: N5222B option 200, 201, 219, 400, 401, or 419.

Specifications are valid under the stated measurement conditions.

- At optical input 1 (“+7 dBm max”). At optical input 2 (“+17 dBm max”), specifications are typically the same for 10 dB higher incident average and modulated optical power.
- For external source optical input (option 050), all specifications are typical. <sup>2, 5, 6</sup>
- For wavelength: (1310 ± 10) nm (option 100, 102).

System performance	DUT response	0.05 GHz to 0.2 GHz	0.2 GHz to 0.7 GHz	0.7 GHz to 20 GHz	20 GHz to 26.5 GHz
Relative frequency response uncertainty <sup>2</sup>	≥ -13 dBe (≥ -6.5 dBo) <sup>3</sup>	± 0.25 dBe, typical (± 0.125 dBo, typ.)	± 0.25 dBe (± 0.125 dBo)	± 0.25 dBe (± 0.125 dBo)	± 0.25 dBe, typical (± 0.125 dBo, typ.)
Absolute frequency response uncertainty <sup>2</sup>	≥ -13 dBe (≥ -6.5 dBo) <sup>3</sup>	± 1.2 dBe, typical (± 0.6 dBo, typical)	± 1.2 dBe (± 0.6 dBo)	± 1.2 dBe (± 0.6 dBo)	± 1.2 dBe, typical (± 0.6 dBo, typical)
Frequency response repeatability (typical) <sup>2</sup>	≥ -13 dBe (≥ -6.5 dBo) <sup>3</sup>	± 0.1 dBe	± 0.1 dBe	± 0.1 dBe	± 0.1 dBe
Min. measurable freq. response (noise floor) <sup>1, 2, 4</sup>	-	-35 dBe (-17.5 dBo)	-60 dBe (-30 dBo)	-64 dBe (-32 dBo)	-64 dBe, typical (-32 dBo, typical)
Phase uncertainty (typical) <sup>2, 7</sup>	≥ -13 dBe <sup>3</sup> (≥ -6.5 dBo)	-	± 2.0°	± 2.0°	± 2.0°
Group delay uncertainty	-	Derived from phase uncertainty, see section “Group delay uncertainty”. Example: ± 2.0° → ± 8 ps (1 GHz aperture)			

<sup>1</sup> IFBW = 10 Hz.

<sup>2</sup> For +4 dBm average output power from LCA optical output.

<sup>3</sup> For DUT response max. +6 dBe (+3 dBo) gain.

<sup>4</sup> Average value over frequency range.

<sup>5</sup> After CW responsivity and user calibration with external source.

<sup>6</sup> Requires option 100 or 102.

<sup>7</sup> Except phase wrap aliasing (Example: A DUT group delay of 5 ns (1 m cable length) requires a frequency step size of ≤ 0.2 GHz to avoid phase wraps).

## Specifications for Optical to Optical Measurements at 1550 nm (O/O Mode)

N4373E with network analyzer: N5222B option 200, 201, 219, 400, 401, or 419.

Specifications are valid under the stated measurement conditions.

- At optical input 1 (“+7 dBm max”). At optical input 2 (“+17 dBm max”), specifications are typically the same for 10 dB higher incident average and modulated optical power.
- For external source optical input (option 050), all specifications are typical. <sup>2, 5, 6</sup>
- For wavelength: (1550 ± 20) nm (option 101, 102).

System performance	DUT response	0.05 GHz to 0.2 GHz	0.2 GHz to 0.7 GHz	0.7 GHz to 20 GHz	20 GHz to 26.5 GHz
Relative frequency response uncertainty <sup>2</sup>	≥ -13 dBe (≥ -6.5 dBo) <sup>3</sup>	± 0.25 dBe, typical (± 0.125 dBo, typ.)	± 0.25 dBe (± 0.125 dBo)	± 0.25 dBe (± 0.125 dBo)	± 0.25 dBe, typical (± 0.125 dBo, typ.)
Absolute frequency response uncertainty <sup>2</sup>	≥ -13 dBe (≥ -6.5 dBo) <sup>3</sup>	± 1.2 dBe, typical (± 0.6 dBo, typical)	± 1.2 dBe (± 0.6 dBo)	± 1.2 dBe (± 0.6 dBo)	± 1.2 dBe, typical (± 0.6 dBo, typical)
Frequency response repeatability (typical) <sup>2</sup>	≥ -13 dBe (≥ -6.5 dBo) <sup>3</sup>	± 0.06 dBe	± 0.02 dBe	± 0.04 dBe	± 0.04 dBe
Min. measurable freq. response (noise floor) <sup>1, 2, 4</sup>	-	-35 dBe (-17.5 dBo)	-60 dBe (-30 dBo)	-64 dBe (-32 dBo)	-64 dBe, typical (-32 dBo, typical)
Phase uncertainty (typical) <sup>2, 7</sup>	≥ -13 dBe <sup>3</sup> (≥ -6.5 dBo)	-	± 2.0°	± 2.0°	± 2.0°
Group delay uncertainty	-	Derived from phase uncertainty, see section “Group delay uncertainty”. Example: ± 2.0° → ± 8 ps (1 GHz aperture)			

<sup>1</sup> IFBW = 10 Hz.

<sup>2</sup> For +4 dBm average output power from LCA optical output.

<sup>3</sup> For DUT response max. +6 dBe (+3 dBo) gain.

<sup>4</sup> Average value over frequency range.

<sup>5</sup> After CW responsivity and user calibration with external source.

<sup>6</sup> Requires option 101 or 102.

<sup>7</sup> Except phase wrap aliasing (Example: A DUT group delay of 5 ns (1 m cable length) requires a frequency step size of ≤ 0.2 GHz to avoid phase wraps).

## Specifications for Electrical-Electrical Measurements (E/E Mode)

All specifications of the N5222B option 200, 201, 219, 400, 401, or 419 Network Analyzer apply depending on selected LCA option x2z. Please see the corresponding Network Analyzer data sheet (pub no. [N5221-90003](#)) and User's Guide.

### Optical Test Set

Electrical loss of optical test set	< 2.0 dBe (typical)
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### Group delay uncertainty

For more details see specifications of the N5222B option 200, 201, 219, 400, 401, or 419 (pub no. [N5221-90003](#)).

### Group delay

Group delay is computed by measuring the phase change within a specified aperture (for aperture see below):

$$GD [s] = \frac{\text{Phase change [deg]}}{\text{Aperture [Hz]} * 360} \quad (\text{Equation 1})$$

### Group delay uncertainty

Is calculated from the specified phase uncertainty and from the aperture (for aperture see below):

$$GD [\pm s] = \frac{\text{Phase uncertainty } [\pm \text{deg}]}{\text{Aperture [Hz]} * 360} * \text{sqrt}(2) \quad (\text{Equation 2})$$

### Aperture

Determined by the frequency span and the number of points per sweep:

Aperture: (frequency span) / (number of points-1)

### GD range


The maximum group delay is limited to measuring no more than  $\pm 180$  degrees of phase change within the selected aperture (see Equation 1).



## General Characteristics

Weight	Net	Packaged
2 port LCA	35.5 kg (78.3 lbs)	52 kg (114.6 lbs)
4 port LCA	45.2 kg (99.6 lbs)	60 kg (132.3 lbs)
Assembled Dimensions (H x W x D)		
413 mm x 438 mm x 538 mm (16.3 in x 17.3 in x 21.2 in)		
Power Requirements		
N5222B	100 to 240 V~, 50 to 60 Hz, max. 450 VA	
Optical test set	100 to 240 V~, 50 to 60 Hz, max. 40 VA	

Shipping Content	
N5222B NA according to ordered option	
2x N4373-61604 0.5m m-f high performance RF cable (4-port network analyzer) or 1x N4373-61604 0.5m m-f high performance RF cable (2-port network analyzer)	
1x N4375E optical test set	
1x N4373-61627 f 3.5 mm to f 3.5 mm RF short cut cable	
3x 81000NI optical adaptor (1x additional 81000NI optical adaptor for external input option 050)	
2x N4373-87907 0.5 m FC/APC - FC/PC patch cord and 1x 1005-0256 FC/FC feedthrough adapter (option 021), or 2x N4373-87906 0.5 m FC/APC - FC/APC patch cord and 1x 1005-1027 FC/FC feedthrough adapter (option 022) (1x PMF patch cord 1.0 m FC/APC narrow key for external input option 050)	
1x 8121-1242 USB cable	
1x 0960-3245 keyboard	
1x 0960-3248 mouse	
1x 5692-0476 calibration certificate, 1x 5962-5955 test data sheet	
1x 4375E-90A01 Getting Started Guide	
1x 4373B-90CD1 LCA support CD	
2x local power cord	
1x 9320-6654 RoHS addendum for photonic T&M products, 1x 9320-6677 RoHS addendum for photonic T&M accessories	

Connectivity	
<b>LCA electrical input</b>	<b>LCA electrical output</b>
3.5 mm (m)	3.5 mm (m)
<b>LCA optical input 1</b>	<b>LCA optical input 2</b>
9 µm single-mode fiber, angled <sup>1</sup> , with Keysight universal adapter	9 µm single-mode fiber, angled <sup>1</sup> , with Keysight universal adapter
<b>LCA external source input (option 050 only)</b>	<b>LCA optical output</b>
9 µm polarization maintaining single-mode fiber, angled <sup>1</sup> , with Keysight universal adapter	9 µm single-mode fiber, angled <sup>1</sup> , with Keysight universal adapter
Storage Temperature Range	
-40 °C to +70 °C	
Operating Temperature Range	
+5 °C to +35 °C	
Humidity	
15% to 80% relative humidity, non-condensing	
Altitude (Operating)	
0 ... 2000 m	
Recommended Recalibration Period	
1 year	
Laser Safety Information	
All laser sources listed above are classified as Class 1M according to IEC 60825-1/2007.	
All laser sources comply with 21 CFR 1040.10 except for deviations pursuant to Laser Notice No. 50, dated 2007-06-24.	
	

<sup>1</sup> The optical test set always has angled connectors. Depending on the selected option (021 straight, 022 angled) the appropriate jumper cable will be delivered. This jumper cable must always be used in front to the optical test set to protect the connectors at the optical test set.

## Ordering Information

The N4375E consists of an optical test set and an electrical network analyzer which are mechanically connected. To protect your network analyzer investment, Keysight offers the integration of an already owned PNA/PNA-X with the optical test set as listed below.

All systems come with Keysight's standard warranty.

LCA N4375E Family Options	
Wavelength options	Description
N4375E-100	1310 nm source optical test set
N4375E-101	1550 nm source optical test set
N4375E-102	1300 nm and 1550 nm source optical test set
Network analyzer options	Description
N4375E-220	26.5 GHz, 2 ports, single source PNA (N5222B-200) and RF-cables
N4375E-221	26.5 GHz, 2 ports, single source PNA (N5222B-201) with configurable test set and RF-cables
N4375E-222	26.5 GHz, 2 ports, single source PNA (N5222B-219) with configurable test set, extended power range, bias-tees and RF-cables
N4375E-420	26.5 GHz, 4 ports, dual source PNA (N5222B-400) and RF-cables
N4375E-421	26.5 GHz, 4 ports, dual source PNA (N5222B-401) with configurable test set and RF-cables
N4375E-422	26.5 GHz, 4 ports, dual source PNA (N5222B-419) with configurable test set, extended power range, bias-tees and RF-cables
N4375E-229	Integration of customer's 26.5 GHz, 2 port PNA (N5222A/B or N5242A/B) with any configuration and RF-cables <sup>1</sup>
N4375E-249	Integration of customer's 26.5 GHz, 4 port PNA (N5222A/B or N5242A/B) with any configuration and RF-cables <sup>1</sup>
Software options	Description
	Refer to the network analyzer configuration guide, pub no. <a href="#">5992-1465EN</a> , for information about other software options
Connector options	Description
N4375E-021	Straight FC/PC SM
N4375E-022	Angled FC/APC SM
Test set options	Description
N4375E-050	External optical input

<sup>1</sup> Guaranteed specifications apply only for the above-mentioned network analyzer options.

Recommended Accessories	
<b>Rack mount kit for network analyzer</b>	<b>Description</b>
1CM042A	Rack mount flange kit - 265.9 mm height for installation without handles
E3663AC	Basic rail kit (for system II instruments)
<b>Rack mount kit for LCA test set</b>	<b>Description</b>
34192A	Rack mount flange kit - 132.6 mm height for installation without handles
E3663AC	Basic rail kit (for system II instruments)
<b>Electrical calibration module</b>	<b>Description</b>
N4691D	Electronic Calibration Module, 26.5 GHz, 3.5 mm, 2-port (option 003, F0F or M0F with 00A recommended)

## Optical Instruments Online Information

Optical test instruments

[www.keysight.com/find/oct](http://www.keysight.com/find/oct)

Lightwave component analyzers

[www.keysight.com/find/lca](http://www.keysight.com/find/lca)

Polarization solutions

[www.keysight.com/find/pol](http://www.keysight.com/find/pol)

Electro-optical converters

[www.keysight.com/find/ref](http://www.keysight.com/find/ref)

Optical test instruments accessories

[www.keysight.com/comms/oct-accessories](http://www.keysight.com/comms/oct-accessories)

Keysight photonic discussion forum

[www.keysight.com/find/photonic\\_forum](http://www.keysight.com/find/photonic_forum)

Learn more at: [www.keysight.com](http://www.keysight.com)

For more information on Keysight Technologies' products, applications or services, please contact your local Keysight office. The complete list is available at:

[www.keysight.com/find/contactus](http://www.keysight.com/find/contactus)

